





2 Description





SN74HC244-Q1 SCLS543C - SEPTEMBER 2002 - REVISED JUNE 2022

SN74HC244-Q1 Octal Buffer and Line Driver With 3-State Outputs

1 Features

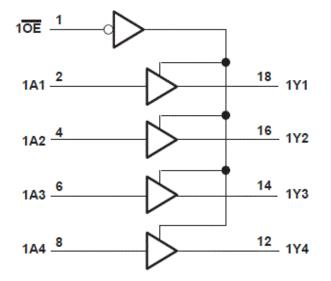
- Qualified for automotive applications
- ESD protection exceeds 2000 V per MIL-STD-883, Method 3015; exceeds 200 V using machine model (C = 200 pF, R = 0)
- Wide operating voltage range of 2 V to 6 V
- High-current outputs drive up to 15 LSTTL loads
- 3-state outputs drive bus lines or buffer memory address registers
- Low power consumption, 80-µA max I_{CC}
- Typical $t_{pd} = 11 \text{ ns}$
- ±6-mA output drive at 5 V
- Low input current of 1 µA max

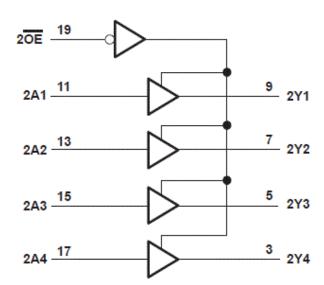
This octal buffer and line driver is designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The SN74HC244 is organized as two 4-bit buffers/ drivers with separate output-enable (OE) inputs. When \overline{OE} is low, the device passes noninverted data from the A inputs to the Y outputs. When \overline{OE} is high, the outputs are in the high-impedance state.

Device Information

PART NUMBER	PACKAGE ⁽¹⁾	BODY SIZE (NOM)		
SN74HC244QDW-Q1	SOIC (20)	12.80 mm × 7.50 mm		
SN74HC244QPW-Q1	TSSOP (20)	6.50 mm × 4.40 mm		

For all available packages, see the orderable addendum at the end of the data sheet.





Functional Block Diagram



Table of Contents

1 Features1	7.2 Functional Block Diagram
2 Description1	
3 Revision History2	
4 Pin Configuration and Functions3	
5 Specifications4	
5.1 Absolute Maximum Ratings4	10 Device and Documentation Support
5.2 Recommended Operating Conditions ⁽¹⁾	10.1 Receiving Notification of Documentation Updates
5.3 Thermal Information4	
5.4 Electrical Characteristics5	10.3 Trademarks
5.5 Switching Characteristics5	10.4 Electrostatic Discharge Caution
5.6 Operating Characteristics5	10.5 Glossary
6 Parameter Measurement Information6	11 Mechanical, Packaging, and Orderable
7 Detailed Description7	
7.1 Overview7	
3 Revision History NOTE: Page numbers for previous revisions may differ	from page numbers in the current version.
Changes from Revision B (February 2022) to Revis	ion C (June 2022) Page
	eased. DW was 58 is now 109.1, PW was 83 is now 131.8
Changes from Revision A (April 2008) to Revision I	3 (February 2022) Page



4 Pin Configuration and Functions

10E	¹ O	20	□□ V _{cc}
1A1 🗀	2	19	2 <u>0E</u>
2Y4 🗀	3	18	1Y1
1A2 🗀	4	17	2A4
2Y3 🗀	5	16	1Y2
1A3 🗀	6	15	2A3
2Y2	7	14	1Y3
1A4	8	13	2A2
2Y1 🗀	9	12	1Y4
GND 💳	10	11	2A1
			ı

DW or PW Package 20-Pin SOIC or TSSOP Top View



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range⁽¹⁾

			MIN	MAX	UNIT
V _{CC}	Supply voltage range	upply voltage range			
I _{IK}	Input clamp current ⁽²⁾	$V_I < 0 \text{ or } V_I > V_{CC}$		±20	mA
I _{OK}	Output clamp current ⁽²⁾	$V_O < 0$ or $V_O > V_{CC}$		±20	mA
Io	Continuous output current	$V_O = 0$ to V_{CC}		±35	mA
	Continuous current through V _{CC} or GN	ID .		±70	mA
TJ	Junction temperature		150	°C	
T _{stg}	Storage temperature range		– 65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5.2 Recommended Operating Conditions⁽¹⁾

			MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage		2	5	6	V
		V _{CC} = 2 V	1.5			
V_{IH}	High-level input voltage	V _{CC} = 4.5 V	3.15			V
		V _{CC} = 6 V	4.2			
V _{IL}		V _{CC} = 2 V			0.5	
	Low-level input voltage	V _{CC} = 4.5 V			1.35	V
		V _{CC} = 6 V			1.8	
VI	Input voltage		0		V _{CC}	V
Vo	Output voltage		0		V _{CC}	V
		V _{CC} = 2 V			1000	
t _t	Input transition (rise and fall) time	V _{CC} = 4.5 V			500	ns
		V _{CC} = 6 V			400	
T _A	Operating free-air temperature	<u>'</u>	-40		125	°C

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

5.3 Thermal Information

		DW (SOIC)	PW (TSSOP)	
THERMAL ME	ETRIC	20 PINS	20 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance ⁽¹⁾	109.1	131.8	°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	76	72.2	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	77.6	82.8	°C/W
ΨЈТ	Junction-to-top characterization parameter	51.5	21.5	°C/W
ΨЈВ	Junction-to-board characterization parameter	77.1	82.4	°C/W
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	N/A	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.

Product Folder Links: SN74HC244-Q1

²⁾ The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



5.4 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V	T,	_A = 25°C		MIN MA	K UNIT
PARAMETER	1231 0	ONDITIONS	V _{cc}	MIN	TYP	MAX	WIN WA	CIVIT
			2 V	1.9	1.998		1.9	
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4	
V _{OH}	$V_I = V_{IH}$ or V_{IL}		6 V	5.9	5.999		5.9	V
		I _{OH} = −6 mA	4.5 V	3.98	4.3		3.7	
		$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.2	
			2 V		0.002	0.1	0.	1
	V _I = V _{IH} or V _{IL}	I _{OL} = 20 μA	4.5 V		0.001	0.1	0.	1
V _{OL}			6 V		0.001	0.1	0	1 V
		I _{OL} = 6 mA	4.5 V		0.17	0.26	0	4
		I _{OL} = 7.8 mA	6 V		0.15	0.26	0	4
I _I	V _I = V _{CC} or 0		6 V		±0.1	±100	±100	0 nA
I _{OZ}	$V_O = V_{CC}$ or 0,	V _I = V _{IH} or V _{IL}	6 V		±0.01	±0.5	±1	0 μΑ
I _{CC}	$V_I = V_{CC}$ or 0,	I _O = 0	6 V			8	16	0 μΑ
C _i			2 V to 6 V		3	10	1	0 pF

5.5 Switching Characteristics

over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) See: (Parameter Measurement Information)

PARAMETER	FROM	то	V	T,	_A = 25°C		MIN	MAY	UNIT
PARAMETER	(INPUT)	(OUTPUT)	V _{CC}	MIN	TYP	MAX	IVIIIN	MAX	UNII
			2 V		40	115		170	
t _{pd}	Α	Y	4.5 V		13	23		34	ns
			6 V		11	20		29	
			2 V		75	150		225	
t _{en}	ŌĒ	Y	4.5 V		15	30		45	ns
			6 V		13	26		38	
			2 V		75	150		225	
t _{dis}	ŌĒ	Y	4.5 V		15	30		45	ns
			6 V		13	26		38	
t _t			2 V		28	60		90	
		Y	4.5 V		8	12		18	ns
			6 V		6	10		15	

5.6 Operating Characteristics

T_A = 25°C

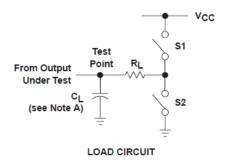
	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per buffer/driver	No load	35	pF

Copyright © 2022 Texas Instruments Incorporated

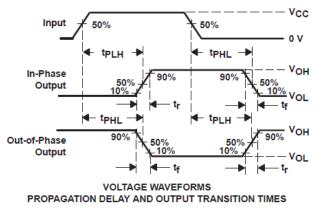
Submit Document Feedback

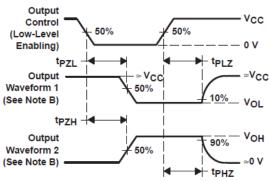


6 Parameter Measurement Information



PARAMETER		RL	CL	S 1	S2
ten	tPZH	1 kΩ	Open 50 pF		Closed
	t _{PZL}	1 K22	50 pr	Closed	Open
t.e.	t _{PHZ}	1 kΩ	50 pF	Open	Closed
^t dis	tPLZ	1 1132	30 pi	Closed	Open
t _{pd} or t _t		1	50 pF	Open	Open





Input 50% 50% 0 V

10% 10% 0 V

VOLTAGE WAVEFORM
INPUT RISE AND FALL TIMES

VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

- A. C_L includes probe and test-fixture capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_f = 6 \text{ ns}$, $t_f = 6 \text{ ns}$.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 6-1. Load Circuit and Voltage Waveforms

Submit Document Feedback

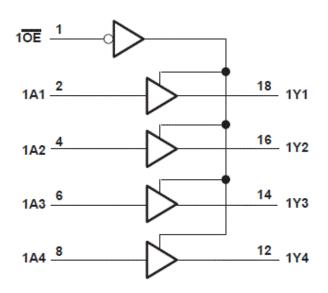
Copyright © 2022 Texas Instruments Incorporated

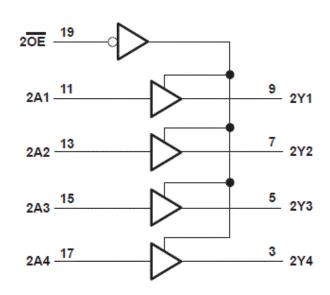
7 Detailed Description

7.1 Overview

This octal buffer and line driver is designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The SN74HC244 is organized as two 4-bit buffers/drivers with separate output-enable (\overline{OE}) inputs. When \overline{OE} is low, the device passes noninverted data from the A inputs to the Y outputs. When \overline{OE} is high, the outputs are in the high-impedance state.

7.2 Functional Block Diagram





7.3 Device Functional Modes

Table 7-1. Function Table (each buffer/driver)

INP	OUTPUT	
ŌĒ	Α	Y
L	Н	Н
L	L	L
Н	Х	Z

8 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1-µF capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1-µF and 1-µF capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

9 Layout

9.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

10.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

www.ti.com 30-Jun-2022

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN74HC244QDWRQ1	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC244Q	Samples
SN74HC244QPWRG4Q1	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC244Q	Samples
SN74HC244QPWRQ1	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC244Q	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

PACKAGE OPTION ADDENDUM

www.ti.com 30-Jun-2022

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN74HC244-Q1:

Catalog: SN74HC244

● Enhanced Product : SN74HC244-EP

Military: SN54HC244

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

• Enhanced Product - Supports Defense, Aerospace and Medical Applications

• Military - QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

www.ti.com 3-Mar-2023

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HC244QDWRQ1	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN74HC244QPWRG4Q1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN74HC244QPWRG4Q1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN74HC244QPWRQ1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN74HC244QPWRQ1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1

www.ti.com 3-Mar-2023



*All dimensions are nominal

The difference die from the										
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)			
SN74HC244QDWRQ1	SOIC	DW	20	2000	367.0	367.0	45.0			
SN74HC244QPWRG4Q1	TSSOP	PW	20	2000	356.0	356.0	35.0			
SN74HC244QPWRG4Q1	TSSOP	PW	20	2000	356.0	356.0	35.0			
SN74HC244QPWRQ1	TSSOP	PW	20	2000	356.0	356.0	35.0			
SN74HC244QPWRQ1	TSSOP	PW	20	2000	356.0	356.0	35.0			



SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



PW (R-PDSO-G20)

PLASTIC SMALL OUTLINE



NOTES:

- All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
 C. Publication IPC-7351 is recommended for alternate design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2023, Texas Instruments Incorporated